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**ELECTRONIC INFORMATION DISCLOSURE STATEMENT**

Electronic Version v18

Stylesheet Version v18.0

Title of Invention	METHOD TO SELECTIVELY CORRECT CRITICAL DIMENSION ERRORS IN THE SEMICONDUCTOR INDUSTRY
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Application Number: 10/710,602

Confirmation Number:

First Named Applicant: Jed Rankin

Attorney Docket Number: BUR920040086US1

Search string: ( 6653231 or 6630288 or 5468595 or 20020160628 or 20020160320 ).pn.

**US Patent Documents**

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

Init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
X	1	6653231	2003-11-25	Okoroanyanwu et al			
X	2	6630288	2003-10-07	Shields et al			
X	3	5468595	1995-11-21	Livesay			

**US Published Applications**

Note: Applicant is not required to submit a paper copy of cited US Published Applications

Init	Cite.No.	Pub. No.	Date	Applicant	Kind	Class	Subclass
X	1	20020160628	2002-10-31	Okoroanyanwu et al			
X	2	20020160320	2002-10-31	Shields et al			

**Signature**

Examiner Name	Date
Matthew Doty	3/21/06